

Notice of References Cited	Application/Control No. 10/663,456		Applicant(s)/Patent Under Reexamination HEDIN ET AL.	
	Examiner Sean Sprigg		Art Unit 3712	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,797,795	08-1998	Takemoto et al.	463/42
*	C	US-2004/0002375	01-2004	Ogawa, Yoshio	463/20
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	M	US-			

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NON-PATENT DOCUMENTS

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